Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/657,296	RIEHL ET AL.	
Examiner	Art Unit	
John P. Lacyk	3735	

	SEAR	CHED	
Class	Subclass	Date	Examiner
600	9-15		
607	63-66,		
	72	6/11/2005	JPL
Updated	above	7/21/2006	JPL
Updated	above	9/26/2006	JPL

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
	ce Search Printout	9/27/2006	JPL	

SEAI (INCLUDING)	RCH NOTES SEARCH STRAT	ΓEGY)
	DA ⁻	
East search	6/11	/05 JPL
Plus search	1/14/2	2005 JPL
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